

ECE 320 - Homework #8

Boolean Logic, DTL, TTL Logic. Due Monday, October 21st

Transistor Data Sheets

- Find the data sheets for a 3904 transistor. From the data sheets, determine

V_{be} @ 20mA

- $I_b = 1\text{mA}$: $0.65\text{V} < V_{be} < 0.85\text{V}$
- $I_b = 5\text{mA}$: $V_{be} < 0.95\text{V}$

$V_{ce(\text{sat})}$

- $I_c = 10\text{mA}$: $V_{ce} < 0.2\text{V}$
- $I_c = 50\text{mA}$: $V_{ce} < 0.3\text{V}$

$h_{FE} = \beta$

- $I_c = 0.1\text{mA}$: $h_{FE} > 40$
- $I_c = 1\text{mA}$: $h_{FE} > 70$
- $I_c = 10\text{mA}$: $100 < h_{FE} < 300$
- $I_c = 50\text{mA}$: $h_{FE} > 60$
- $I_c = 100\text{mA}$: $h_{FE} > 30$

$I_{c(\text{max})}$

- 200mA

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2N3904BU

[Datasheet](#)

Digi-Key Part Number	2N3904FS-ND
Manufacturer	ON Semiconductor
Manufacturer Part Number	2N3904BU
Description	TRANS NPN 40V 0.2A TO-92
Manufacturer Standard Lead Time	6 Weeks
Detailed Description	Bipolar (BJT) Transistor NPN 40V 200mA 300MHz 625mW Through Hole TO-92-3

Absolute Maximum Ratings^{(1), (2)}

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only. Values are at $T_A = 25^\circ\text{C}$ unless otherwise noted.

Symbol	Parameter	Value	Unit
V_{CEO}	Collector-Emitter Voltage	40	V
V_{CBO}	Collector-Base Voltage	60	V
V_{EBO}	Emitter-Base Voltage	6.0	V
I_c	Collector Current - Continuous	200	mA
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to 150	°C

ON CHARACTERISTICS⁽⁵⁾

h_{FE}	DC Current Gain	$I_c = 0.1\text{ mA}, V_{CE} = 1.0\text{ V}$	40		
		$I_c = 1.0\text{ mA}, V_{CE} = 1.0\text{ V}$	70		
		$I_c = 10\text{ mA}, V_{CE} = 1.0\text{ V}$	100	300	
		$I_c = 50\text{ mA}, V_{CE} = 1.0\text{ V}$	60		
		$I_c = 100\text{ mA}, V_{CE} = 1.0\text{ V}$	30		
$V_{CE(\text{sat})}$	Collector-Emitter Saturation Voltage	$I_c = 10\text{ mA}, I_B = 1.0\text{ mA}$		0.2	V
		$I_c = 50\text{ mA}, I_B = 5.0\text{ mA}$		0.3	
$V_{BE(\text{sat})}$	Base-Emitter Saturation Voltage	$I_c = 10\text{ mA}, I_B = 1.0\text{ mA}$	0.65	0.85	V
		$I_c = 50\text{ mA}, I_B = 5.0\text{ mA}$		0.95	

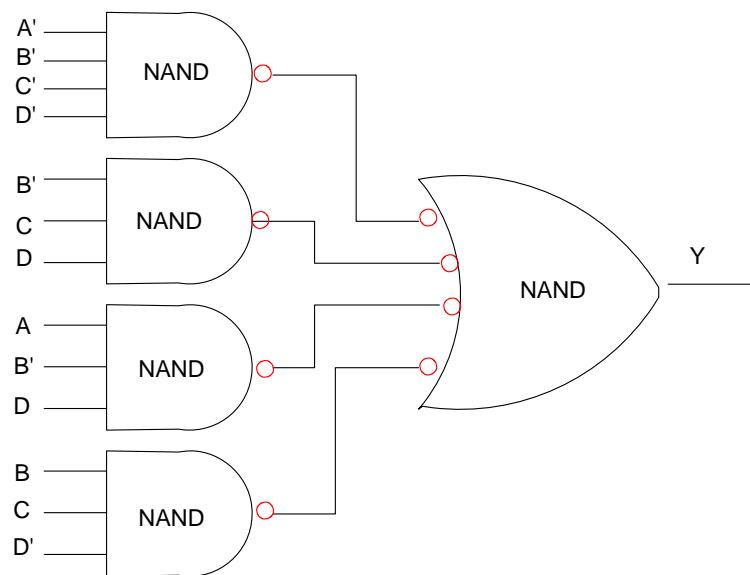
Boolean Logic

- 2) Design a circuit using NAND gates to implement $Y(A,B,C,D)$ (i.e. circle the 1's)

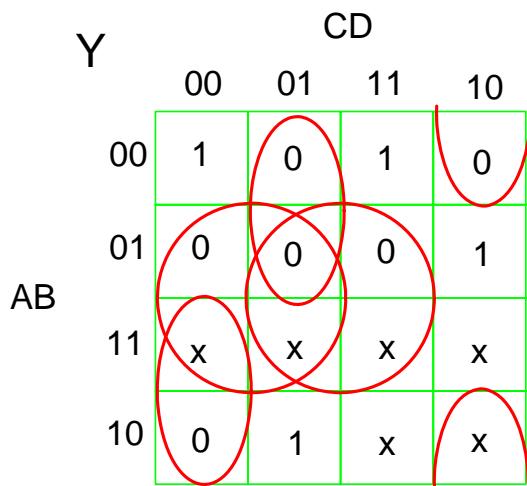
		CD				
		00	01	11	10	
AB		00	1	0	1	0
01		0	0	0	1	
11		x	x	x	x	
10		0	1	x	x	

This gives

$$Y = \overline{A}\overline{B}\overline{C}\overline{D} + \overline{B}CD + A\overline{B}D + BCD$$



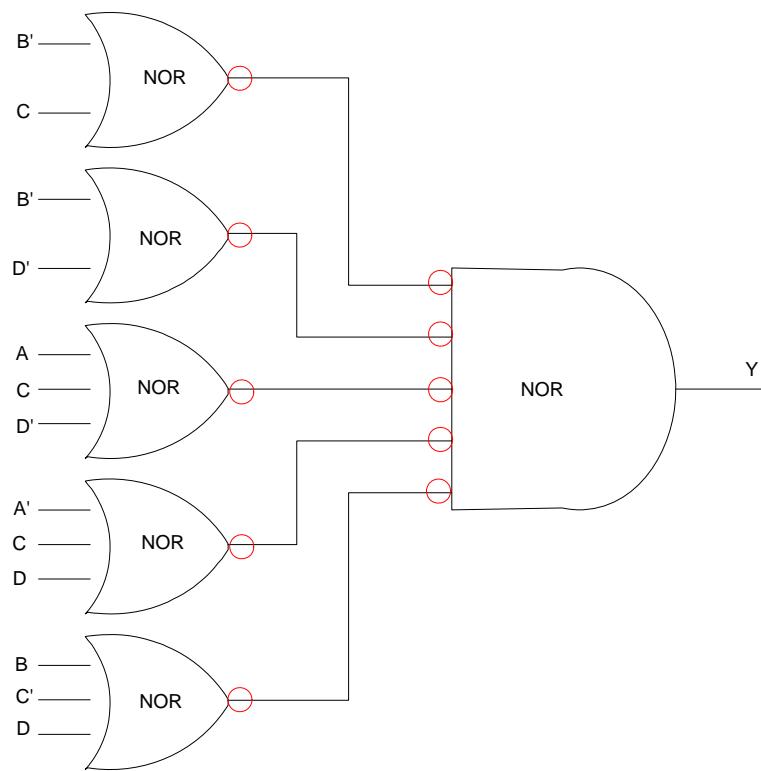
3) Design a circuit using NOR gates to implement $Y(A,B,C,D)$ (i.e. circle the 0's)



$$\bar{Y} = B\bar{C} + BD + \bar{A}\bar{C}\bar{D} + A\bar{C}\bar{D} + \bar{B}C\bar{D}$$

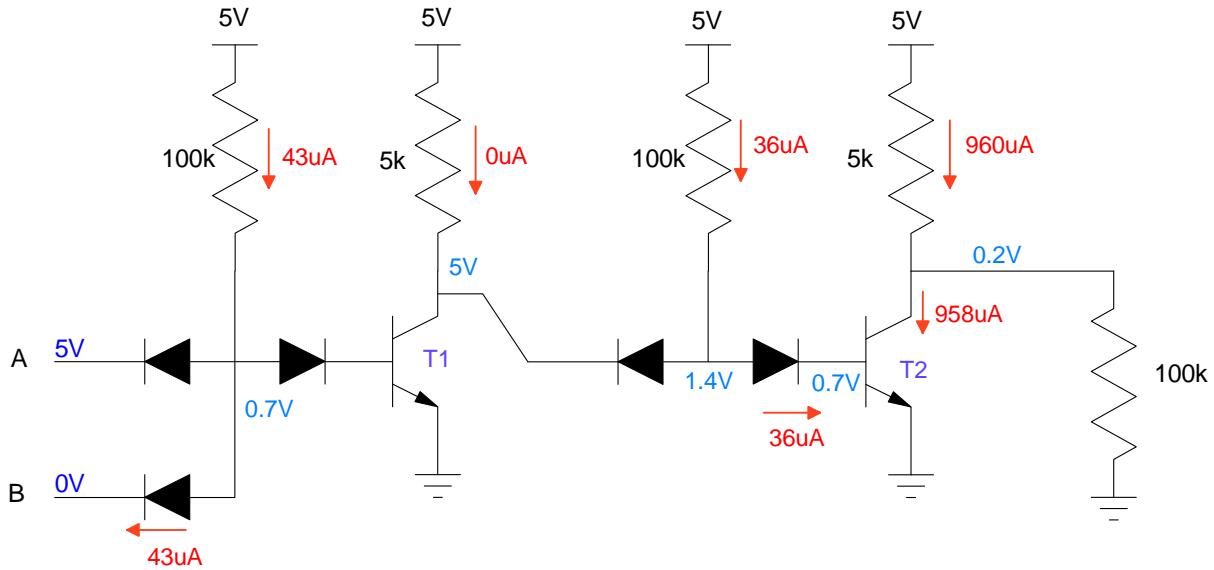
Use DeMorgan's theorem

$$Y = (\bar{B} + C)(\bar{B} + \bar{D})(A + C + \bar{D})(\bar{A} + C + D)(B + \bar{C} + D)$$



DTL Logic

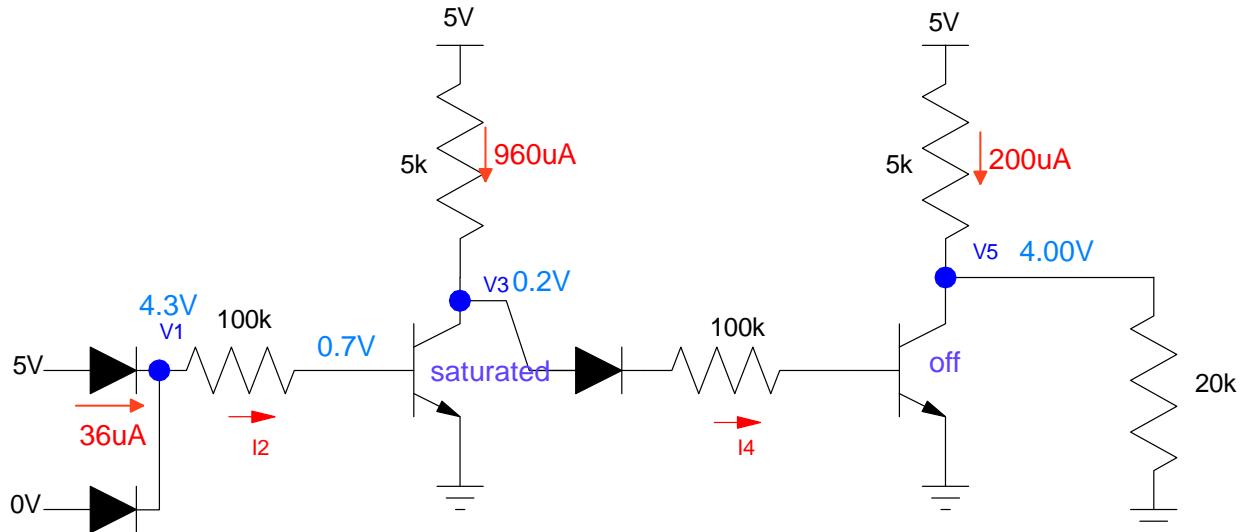
- 4) Determine the voltages and currents for the following DTL AND gate. Assume 3904 transistors (from problem #1)



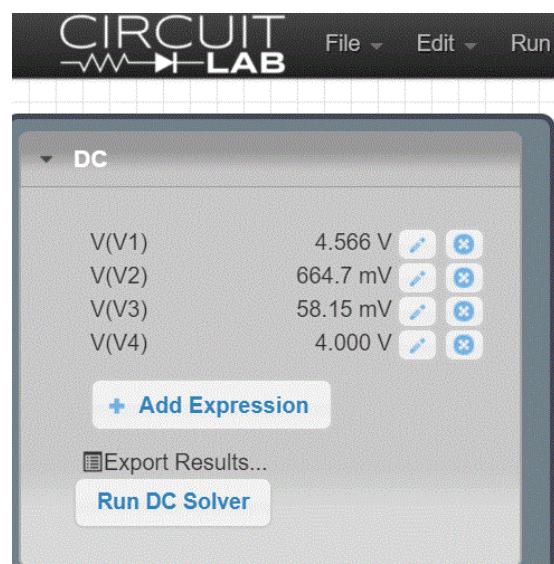
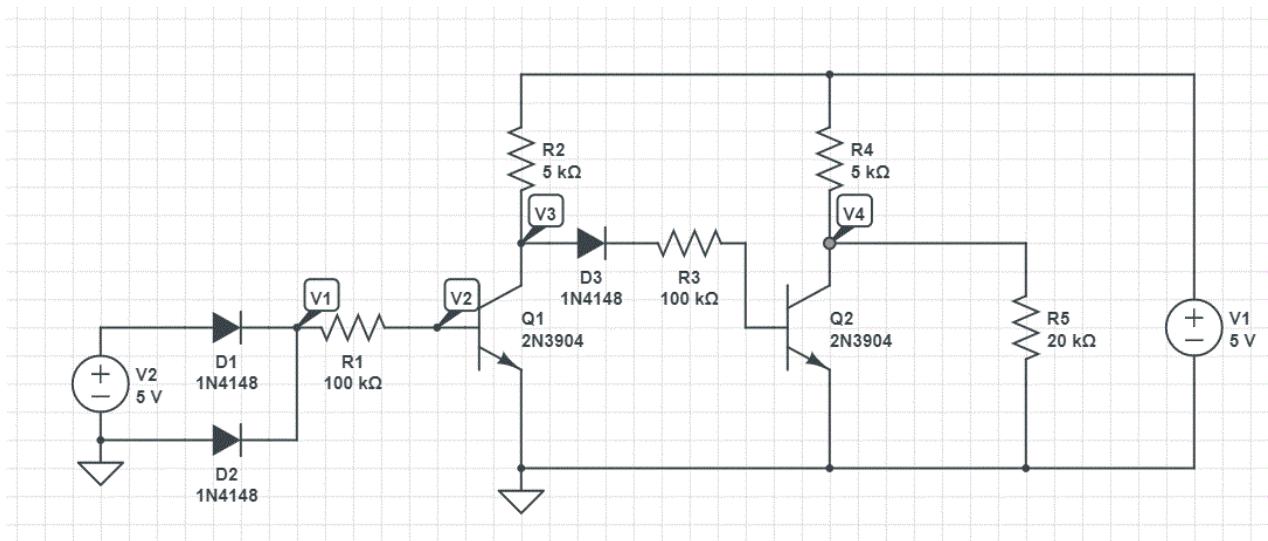
Transistor T2 is saturated

$$\beta I_b = 3.6mA > 958\mu A$$

- 5) Determine the voltages and currents for the following DTL OR gate. Assume 3904 transistors

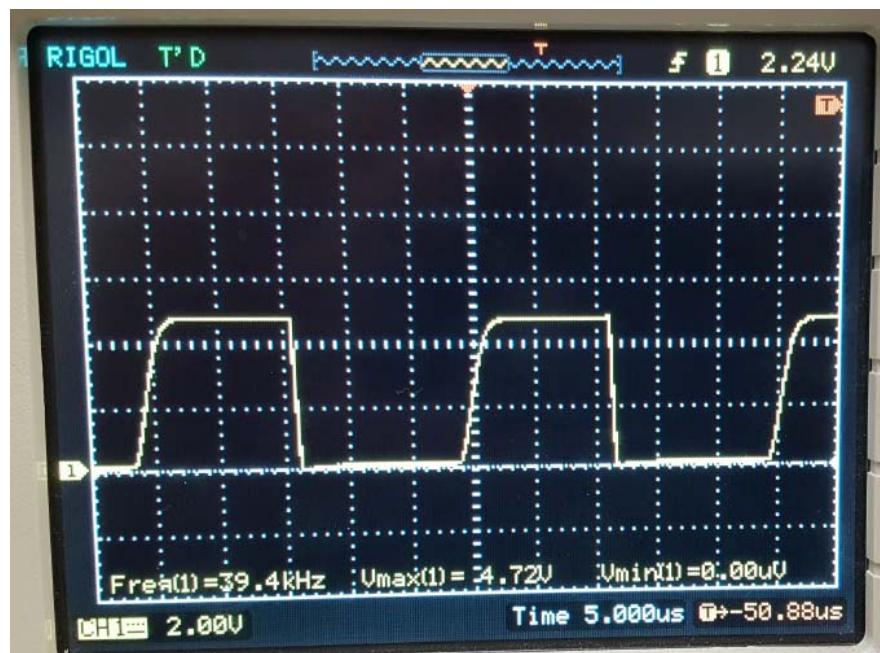


- 6) Check your analysis for problem #5 (DTL OR) in PartSim (or similar program)

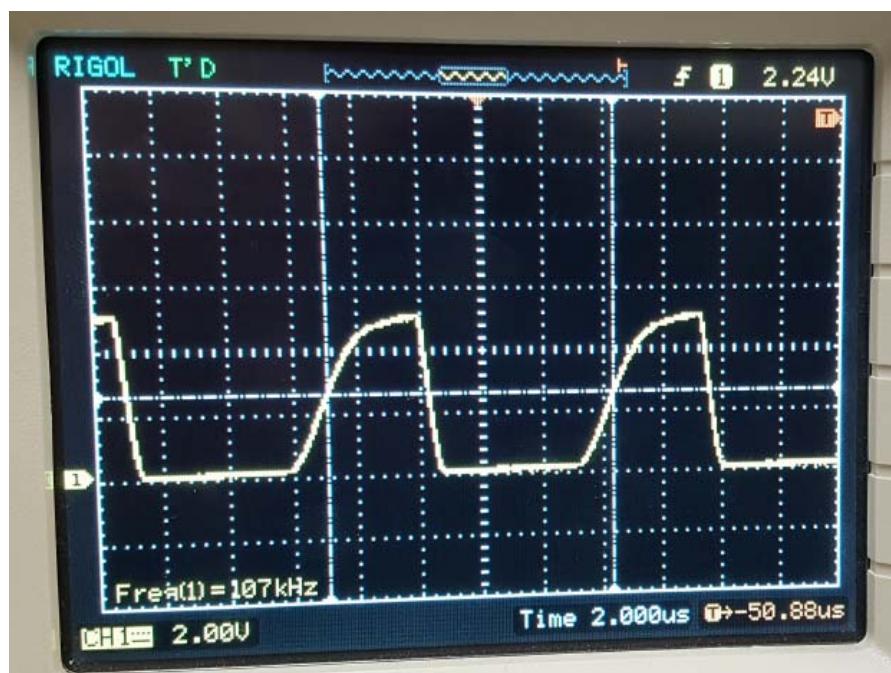


7) (Lab): Build a DTL OR gate in lab. Measure

- The voltages when the input is { 0V, 0V },
- The voltages when the input is { 0V, 5V }, and
- The maximum frequency the logic gate can respond to (apply a square wave at the input)



"True" = 4.72V, "False" = 0.00V



Maximum Frequency = 107kHz (approx)

TTL Logic

8) Determine the voltages for the following TTL inverter. Assume 2n222 transistors.

$$\beta = 100 \quad c \text{ to } e$$

$$\beta = 4 \quad e \text{ to } c$$

